

## N-Channel 650V (D-S) Super Junction Power MOSFET

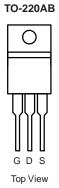
PRODUCT SUMMARY					
V <sub>DS</sub> (V) at T <sub>J</sub> max.	700				
R <sub>DS(on)</sub> at 25 °C (Ω)	V <sub>GS</sub> = 10 V	0.5			
Q <sub>g</sub> max. (nC)	25				
Q <sub>gs</sub> (nC)	2.0				
Q <sub>gd</sub> (nC)	2.7				
Configuration	Single				

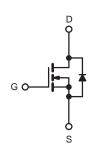
#### **FEATURES**

- $\bullet$  Low figure-of-merit (FOM)  $R_{on} \ x \ Q_g$
- Low input capacitance (Ciss)
- Reduced switching and conduction losses
- Ultra low gate charge (Qq)
- Avalanche energy rated (UIS)

#### **APPLICATIONS**

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- - High-intensity discharge (HID)
  - Fluorescent ballast lighting
- Industrial





N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)					
PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V <sub>DS</sub>	650	V
Gate-Source Voltage			$V_{GS}$	± 30	v
Continuous Drain Current (T <sub>J</sub> = 150 °C)	\/ at 10 \/	$T_{\rm C} = 25  ^{\circ}{\rm C}$ $T_{\rm C} = 100  ^{\circ}{\rm C}$	I <sub>D</sub>	9	
	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 100 °C		6	А
Pulsed Drain Current a			I <sub>DM</sub>	21	
Linear Derating Factor				1.5	W/°C
Single Pulse Avalanche Energy b			E <sub>AS</sub>	186	mJ
Maximum Power Dissipation			P <sub>D</sub>	123	W
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C
Drain-Source Voltage Slope	$T_J = 1$	25 °C	ما/ //ما±	50	1//20
Reverse Diode dV/dt <sup>d</sup>			dV/dt	4.5	V/ns
Soldering Recommendations (Peak Temperature) c	ering Recommendations (Peak Temperature) c for 10 s			300	°C

- a. Repetitive rating; pulse width limited by maximum junction temperature. b.  $V_{DD}=50$  V, starting  $T_J=25$  °C, L=28.2 mH,  $R_g=25$   $\Omega$ ,  $I_{AS}=3.5$  A.
- c. 1.6 mm from case.
- d.  $I_{SD} \le I_D$ ,  $dI/dt = 100 \text{ A/}\mu\text{s}$ , starting  $T_J = 25 \,^{\circ}\text{C}$ .



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	63	°C/W		
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.6	G/ VV		

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static				•	•	•	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA		650	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, I <sub>D</sub> = 1 mA		-	0.65	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$		2	-	4	V
		V <sub>GS</sub> = ± 20 V		-	-	± 100	nA
Gate-Source Leakage	$I_{GSS}$		V <sub>GS</sub> = ± 30 V		-	± 1	μA
			$V_{DS} = 600 \text{ V}, V_{GS} = 0 \text{ V}$		-	1	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>		', V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	10	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 4 A	-	0.50	-	Ω
Forward Transconductance	9 <sub>fs</sub>		= 30 V, I <sub>D</sub> = 4 A	-	16	-	S
Dynamic		-		1	1	1	
Input Capacitance	C <sub>iss</sub>		V = 0 V	-	360	T -	
Output Capacitance	C <sub>oss</sub>	1	$V_{GS} = 0 \text{ V},$ $V_{DS} = 100 \text{ V},$ f = 1  MHz		25	-	pF
Reverse Transfer Capacitance	C <sub>rss</sub>	7			12	-	
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	V <sub>DS</sub> = 0 V to 520 V, V <sub>GS</sub> = 0 V		-	45	-	
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>			-	62	-	
Total Gate Charge	Qg			-	25		†
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	$V_{GS} = 10 \text{ V}$ $I_{D} = 4 \text{ A}, V_{DS} = 520 \text{ V}$		2.0	-	nC
Gate-Drain Charge	Q <sub>gd</sub>	1		-	2.7	-	1
Turn-On Delay Time	t <sub>d(on)</sub>		$V_{DD} = 520 \text{ V}, I_D = 4 \text{ A}, V_{GS} = 10 \text{ V}, R_a = 9.1 \Omega$		25	-	ns
Rise Time	t <sub>r</sub>	Von			55	-	
Turn-Off Delay Time	t <sub>d(off)</sub>	00			70	-	
Fall Time	t <sub>f</sub>	1		-	40	-	
Gate Input Resistance	R <sub>g</sub>	f = 1 MHz, open drain		-	3.5	-	Ω
Drain-Source Body Diode Characteristic	S						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	7	
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	18	- A
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 4 A, V <sub>GS</sub> = 0 V		-	-	1.5	V
Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = I <sub>S</sub> = 4 A, dl/dt = 100 A/μs, V <sub>R</sub> = 400 V		-	190	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>			-	2.3	-	μC
Reverse Recovery Current	I <sub>RRM</sub>			<u> </u>	10	<del> </del>	A

#### Notes

- a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .



### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

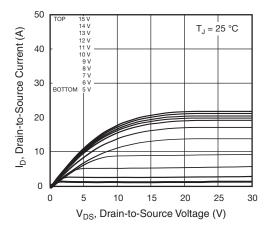


Fig. 1 - Typical Output Characteristics

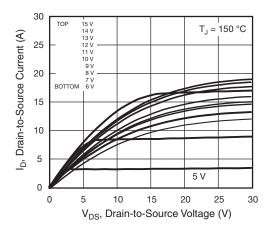


Fig. 2 - Typical Output Characteristics

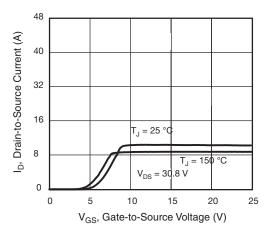


Fig. 3 - Typical Transfer Characteristics

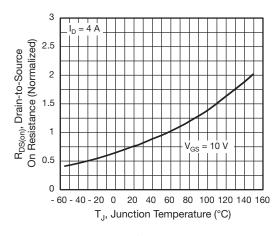


Fig. 4 - Normalized On-Resistance vs. Temperature

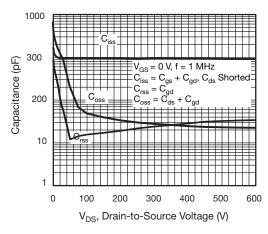


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

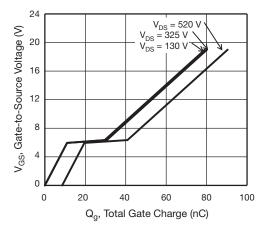


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



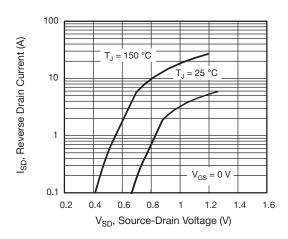


Fig. 7 - Typical Source-Drain Diode Forward Voltage

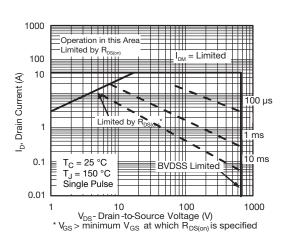


Fig. 8 - Maximum Safe Operating Area

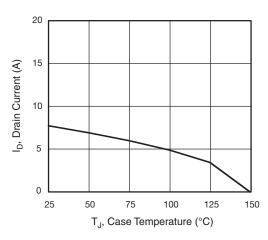


Fig. 9 - Maximum Drain Current vs. Case Temperature

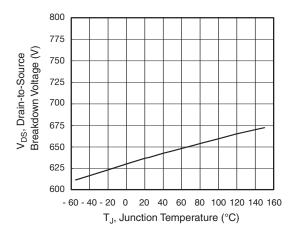


Fig. 10 - Temperature vs. Drain-to-Source Voltage

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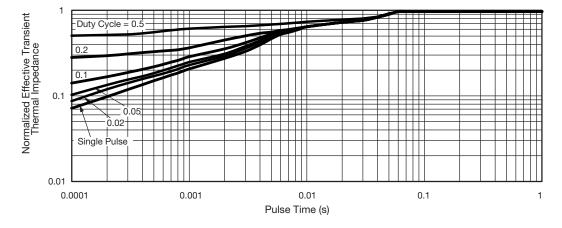


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



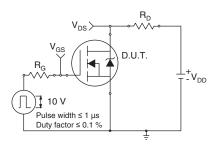


Fig. 12 - Switching Time Test Circuit

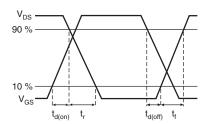


Fig. 13 - Switching Time Waveforms

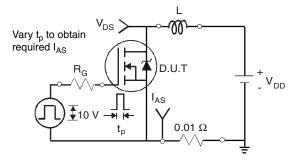


Fig. 14 - Unclamped Inductive Test Circuit

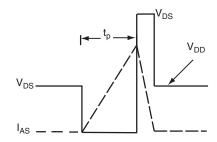


Fig. 15 - Unclamped Inductive Waveforms

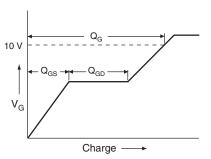


Fig. 16 - Basic Gate Charge Waveform

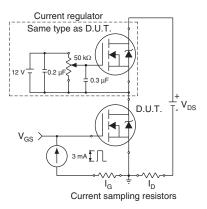
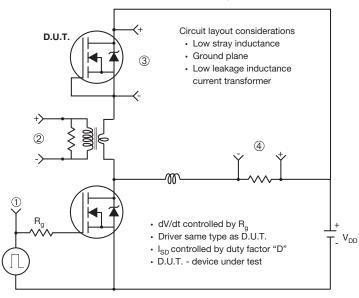


Fig. 17 - Gate Charge Test Circuit



#### Peak Diode Recovery dV/dt Test Circuit



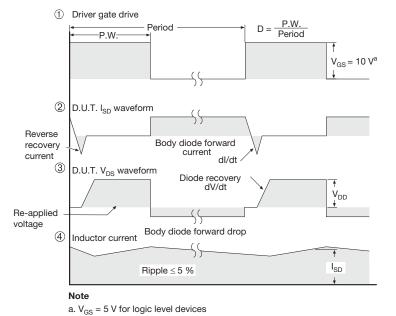
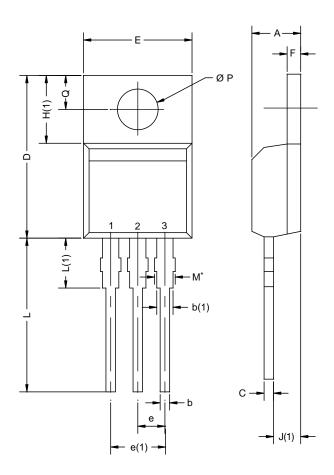


Fig. 18 - For N-Channel



## **TO-220AB**



	MILLIMETERS		INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471					

#### Notes

<sup>\*</sup> M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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